

UMF Equipment - Prism Coupler System

Metricon 2010

The Metricon 2010 is a compact system designed to rapidly and accurately measure both the thickness and the refractive index of dielectric, polymer films and bulk materials. Prism coupling measurements treating the thin film to be measured as an optical waveguide, measuring the angles at which the thin film waveguide will propagate light, and then calculating film thickness and refractive index from the observed mode angles. Measurements of thickness and index can be made on most samples with thickness up to 10-15 microns and minimal sample preparation. For thin films and bulk materials, the system is able to obtain high level of index accuracy and a routine refractive index resolution of ± 0.0003 . Examples of films and bulk materials to be measured: materials not strongly absorbing at the measurement wavelength, polymers, photoresists, epoxies, ITO, GaN, liquid crystals, quartz, sapphire, PET etc.

Features:

- Insensitivity to optical properties of substrates
- User-friendly proprietary fitting software available
- Diode sources: 633 nm and 1547 nm HeNe
- Prisms: #200-P-2, #200-P-4, #200-P-60

Please refer to supplier information page for further details of the system:

<https://www.metricon.com/model-2010-m-overview>

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